
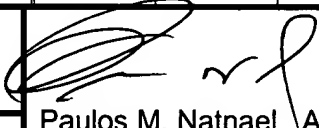
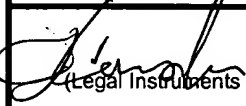


<b>Issue Classification</b> 	<b>Application/Control No.</b>		<b>Applicant(s)/Patent under Reexamination</b>	
	09/487,729		HAN, BAIK-HEE	
	<b>Examiner</b>		<b>Art Unit</b>	
	Paulos M. Natnael		2614	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
348		732							
INTERNATIONAL CLASSIFICATION									
H	0	4	N	5/50					
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				/					
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(Assistant Examiner) (Date)		 Paulos M. Natnael August 2, 2005 (Primary Examiner) (Date)	<b>Total Claims Allowed: 6</b>	
 8-8-05 (Legal Instruments Examiner) (Date)			O.G. Print Claim(s) 1	O.G. Print Fig. 2

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant										<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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